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<u>MOSFET</u> – Single N-Channel, SUPERFET[®] III, FRFET[®]

650 V, 46 A, 65 mΩ

NVHL065N65S3F

Features

- Ultra Low Gate Charge & Low Effective Output Capacitance
- Lower FOM (R_{DS(on) max.} x Q_{g typ.} & R_{DS(on) max.} x E_{OSS})
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

MAXIMUM RATINGS ($T_C = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	V _{DSS}	650	V
Gate-to-Source Voltage - DC	V _{GSS}	±30	V
Gate-to-Source Voltage - AC (f > 1 Hz)	V _{GSS}	±30	V
Drain Current – Continuous ($T_C = 25^{\circ}C$)	۱ _D	46	А
Drain Current – Continuous ($T_C = 100^{\circ}C$)	۱ _D	30	А
Drain Current – Pulsed (Note 3)	I _{DM}	115	А
Power Dissipation $(T_C = 25^{\circ}C)$	PD	337	W
Power Dissipation – Derate Above 25°C	PD	2.7	W/°C
Operating Junction and Storage Temperature Range	T _J , T _{STG}	–55 to +150	°C
Single Pulsed Avalanche Energy (Note 4)	E _{AS}	635	mJ
Repetitive Avalanche Energy (Note 3)	E _{AR}	3.37	mJ
MOSFET dv/dt	dv/dt	100	V/ns
Peak Diode Recovery dv/dt (Note 5)	dv/dt	50	V/ns
Max. Lead Temperature for Soldering Purposes $(1/8'')$ from case for 5 s)	ΤL	300	°C

THERMAL CHARACTERISTICS

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case, Max. (Notes 1, 2)	$R_{\theta JC}$	0.37	°C/W
Thermal Resistance, Junction-to-Ambient, Max. (Notes 1, 2)	R_{\thetaJA}	40	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. The entire application environment impacts the thermal resistance values shown. They are not constants and are only valid for the particular conditions noted.

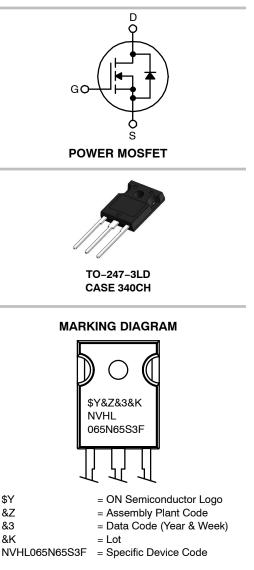
- 2. Assembled to an infinite heatsink with perfect heat transfer from the case (assumes 0 K/W thermal interface).
- 3. Repetitive rating: pulse-width limited by maximum junction temperature.
- 4. $I_{AS} = 9 \text{ A}, R_G = 25 \Omega$, starting $T_J = 25^{\circ}C$. 5. $I_{SD} \le 32.5 \text{ A}, \text{ di/dt} \le 200 \text{ A/}\mu\text{s}, V_{DD} \le 400 \text{ V}, \text{ starting } T_J = 25^{\circ}C$.



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V _{DSS}	R _{DS(ON)} MAX	I _D MAX
650 V	65 mΩ @ 10 V	46 A



ORDERING INFORMATION

Device	Package	Shipping
NVHL065N65S3F	TO-247-4LD (Pb-Free)	30 Units / Tube

ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
OFF CHARACTERISTICS	4		•	•		·
Drain-to-Source Breakdown Voltage	BV _{DSS}	V_{GS} = 0 V, I _D = 1 mA, T _J = 25°C	650			V
Drain-to-Source Breakdown Voltage	BV _{DSS}	V_{GS} = 0 V, I _D = 10 mA, T _J = 150°C				V
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS}/ \Delta T_J$	I _D = 15 mA, Referenced to 25°C		630		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$			10	μA
		V_{DS} = 520 V, T_C = 125°C		153		
Gate-to-Body Leakage Current	I _{GSS}	V_{GS} = ±30 V, V_{DS} = 0 V			±100	nA
ON CHARACTERISTICS			•			
Gate Threshold Voltage	V _{GS(th)}	$V_{GS} = V_{DS}, I_D = 1.3 \text{ mA}$	3.0		5.0	V
Threshold Temperature Coefficient	$\Delta V_{GS(th)} / \Delta T_J$	$V_{GS} = V_{DS}, I_D = 1.3 \text{ mA}$		-8.6		mV/°C
Static Drain-to-Source On Resistance	R _{DS(on)}	V_{GS} = 10 V, I _D = 23 A		54	65	mΩ
Forward Transconductance	9 _{FS}	$V_{DS} = 20 \text{ V}, \text{ I}_{D} = 23 \text{ A}$		31		S
DYNAMIC CHARACTERISTICS				•	ł	
Input Capacitance	C _{iss}			4075		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, V _{DS} = 400 V, f = 1 MHz		95		
Reverse Transfer Capacitance	C _{rss}			11		
Effective Output Capacitance	C _{oss(eff.)}	V_{DS} = 0 V to 400 V, V_{GS} = 0 V		876		pF
Energy Related Output Capacitance	C _{oss(er.)}	V_{DS} = 0 V to 400 V, V_{GS} = 0 V		160		pF
Total Gate Charge at 10 V	Q _{G(TOT)}			98		nC
Gate-to-Source Gate Charge	Q _{GS}	V _{GS} = 10 V, V _{DS} = 400 V, I _D = 23 A (Note 6)		30		
Gate-to-Drain "Miller" Charge	Q _{GD}	(1010-0)		38		
Equivalent Series Resistance	ESR	f = 1 MHz		1.5		Ω
SWITCHING CHARACTERISTICS					1	
Turn-On Delay Time	t _{d(on)}			34		ns
Turn-On Rise Time	t _r	$V_{GS} = 10 \text{ V}, V_{DD} = 400 \text{ V},$		31		ns
Turn-Off Delay Time	t _{d(off)}	I _D = 23 A, R _g = 2.7 Ω (Note 6)		78		ns
Turn-Off Fall Time	t _f			16		ns
SOURCE-DRAIN DIODE CHARACTER	ISTICS		•	•	•	+
Maximum Continuous Source-to- Drain Diode Forward Current	۱ _S	V _{GS} = 0 V			46	A
Maximum Pulsed Source-to-Drain Diode Forward Current	I _{SM}	V _{GS} = 0 V		115	A	
Source-to-Drain Diode Forward Voltage	V _{SD}	V _{GS} = 0 V, I _{SD} = 23 A			1.3	V
Reverse Recovery Time	t _{rr}			116		ns
Charge Time	ta	V_{GS} = 0 V, dI _F /dt = 100 A/µs,		90		1
Discharge Time	t _b	$I_{SD} = 23 \text{ A}$		24		1
Reverse Recovery Charge	Q _{rr}	1		488		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
6. Essentially independent of operating temperature typical characteristics.

TYPICAL PERFORMANCE CHARACTERISTICS

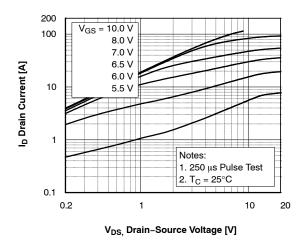
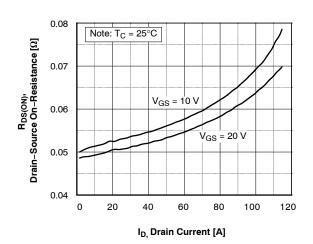
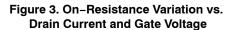


Figure 1. On-Region Characteristics





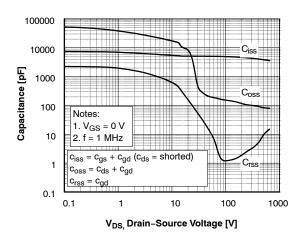


Figure 5. Capacitance Characteristics

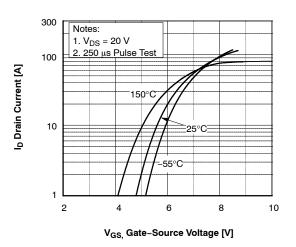
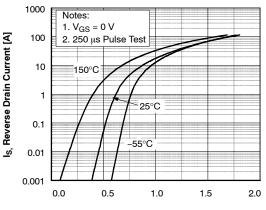


Figure 2. Transfer Characteristics



V_{SD,} Body Diode Forward Voltage [V]

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

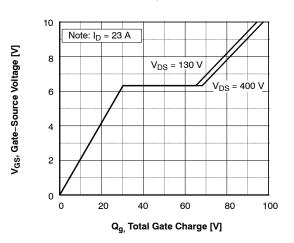
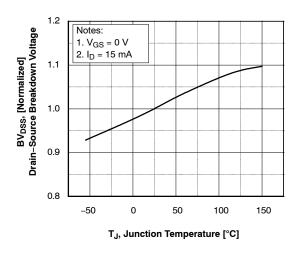
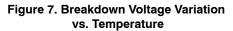


Figure 6. Gate Charge Characteristics

TYPICAL PERFORMANCE CHARACTERISTICS (Continued)





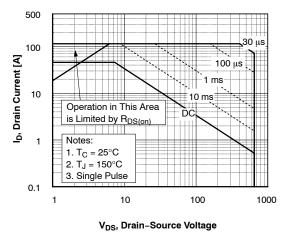


Figure 9. Maximum Safe Operating Area

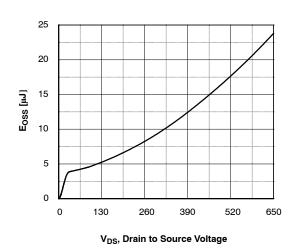


Figure 11. Eoss vs. Drain to Source Voltage

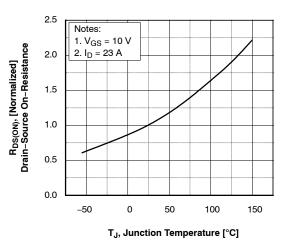


Figure 8. On–Resistance Variation vs. Temperature

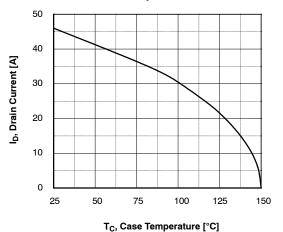


Figure 10. Maximum Drain Current vs. Case Temperature

TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

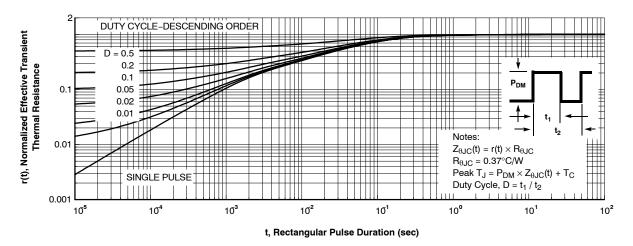


Figure 12. Transient Thermal Response Curve

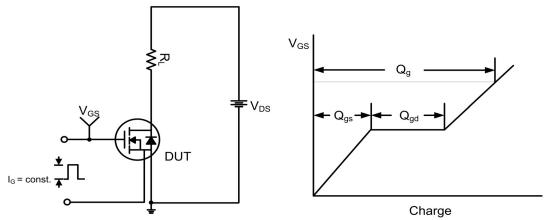


Figure 13. Gate Charge Test Circuit & Waveform

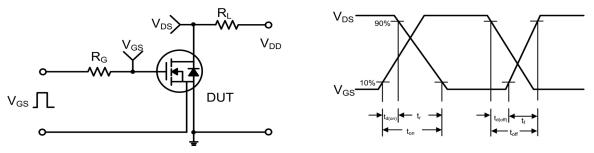
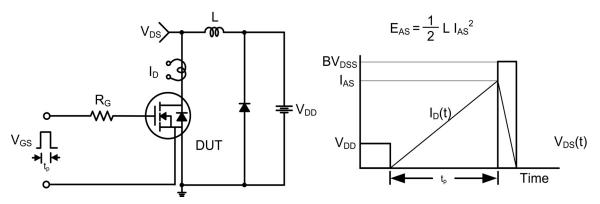


Figure 14. Resistive Switching Test Circuit & Waveforms





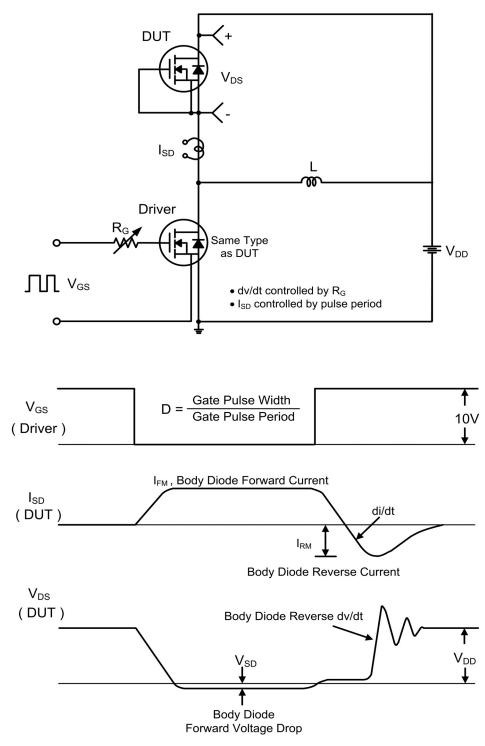
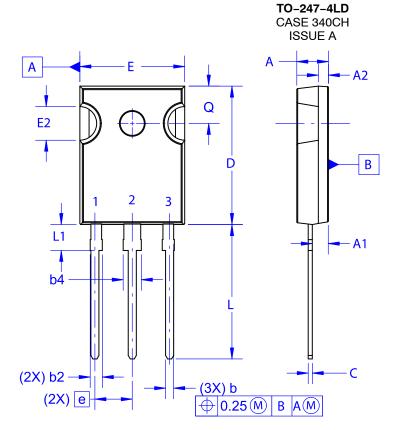


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

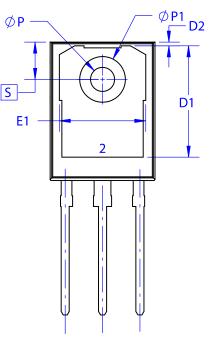
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PACKAGE DIMENSIONS



NOTES: UNLESS OTHERWISE SPECIFIED.

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B. ALL DIMENSIONS ARE IN MILLIMETERS.
C. DRAWING CONFORMS TO ASME Y14.5 - 2009.
D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.



DIM	MILLIMETERS		
DIM	MIN	NOM	MAX
Α	4.58	4.70	4.82
A1	2.29	2.475	2.66
A2	1.40	1.50	1.60
D	20.32	20.57	20.82
E	15.37	15.62	15.87
E2	4.96	5.08	5.20
е	~	5.56	~
L	19.75	20.00	20.25
L1	3.69	3.81	3.93
ØР	3.51	3.58	3.65
Q	5.34	5.46	5.58
S	5.34	5.46	5.58
b	1.17	1.26	1.35
b2	1.53	1.65	1.77
b4	2.42	2.54	2.66
С	0.51	0.61	0.71
D1	13.08	~	~
D2	0.51	0.93	1.35
E1	12.81	~	~
Ø P 1	6.61	6.73	6.85

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